

P-Ch MOSFET

General Description

The WST3401S is the highest performance trench P-Ch MOSFET with extreme high cell density , which provide excellent R_{DSON} and gate charge for most of the small power switching and load switch applications.

The WST3401S meet the RoHS and Green Product requirement with full function reliability approved.

Features

- Advanced high cell density Trench technology
- Super Low Gate Charge
- Excellent Cdv/dt effect decline
- Green Device Available

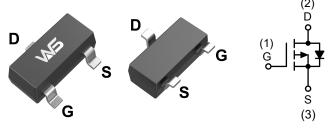
Product Summery

BV _{DSS}	R _{DSON}	I _D
-30V	65mΩ	-3.2A

Applications

- High Frequency Point-of-Load Synchronous s Small power switching for MB/NB/UMPC/VGA
- Networking DC-DC Power System
- Load Switch

SOT-23L Pin Configuration



Absolute Maximum Ratings

Symbol	Parameter	Rating	Units	
V _{DS}	Drain-Source Voltage	-30	V	
V _{GS}	Gate-Source Voltage	±20	V	
I _D @T₀=25℃	Continuous Drain Current, V _{GS} @ -4.5V ¹	-3.2	А	
I _D @T₀=70°C	Continuous Drain Current, V _{GS} @ -4.5V ¹	-2.2	А	
I _{DM}	Pulsed Drain Current ²	-15.5	А	
P _D @T _A =25℃	Total Power Dissipation ³	1	W	
T _{STG}	Storage Temperature Range	-55 to 150	°C	
TJ	Operating Junction Temperature Range	-55 to 150	°C	

Thermal Data

Symbol	Parameter	Тур.	Max.	Unit
R _{eja}	Thermal Resistance Junction-ambient ¹		125	°C/W
R _{θJC}	Thermal Resistance Junction-Case ¹		80	°C/W



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Electrical Characteristics (T_J=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit	
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =-250uA	-30			V	
$\triangle BV_{DSS} / \triangle T_{J}$	BVDSS Temperature Coefficient	Reference to 25 $^\circ\!\mathrm{C}$, I_D=-1mA		-0.01		V/℃	
D	Static Drain-Source On-Resistance ²	V _{GS} =-4.5V , I _D =-3A		65	85		
R _{DS(ON)}	Static Drain-Source On-Resistance	V _{GS} =-2.5V , I _D =-2A		95	125	mΩ	
V _{GS(th)}	Gate Threshold Voltage		-0.5	-0.7	-1.2	V	
$ riangle V_{GS(th)}$	V _{GS(th)} Temperature Coefficient	V _{GS} -V _{DS} , ID2500A		2.98		mV/℃	
	Drain Source Leekage Current	$V_{\text{DS}}\text{=-10V}$, $V_{\text{GS}}\text{=}0\text{V}$, $T_{\text{J}}\text{=}25^\circ\!\mathrm{C}$			-1		
I _{DSS}	Drain-Source Leakage Current	ain-Source Leakage Current $V_{DS} = 10^{\circ}$, $V_{dS} = 0^{\circ}$, $V_{J} = 55^{\circ}$			-5	5 uA	
I _{GSS}	Gate-Source Leakage Current	$V_{GS}=\pm8V$, V_{DS} =0V			±100	nA	
gfs	Forward Transconductance	V _{DS} =-5V , I _D =-3A		9		S	
Qg	Total Gate Charge (-4.5V)			9.7	13.6		
Q _{gs}	Gate-Source Charge	$V_{\text{DS}}\text{=-10V}$, $V_{\text{GS}}\text{=-4.5V}$, $I_{\text{D}}\text{=-3A}$		2.05	2.9	nC	
Q _{gd}	Gate-Drain Charge			2.43	3.4		
T _{d(on)}	Turn-On Delay Time			4.8	9.6		
Tr	Rise Time	$V_{DD}\text{=-10V}$, $V_{GS}\text{=-4.5V}$, $R_{G}\text{=}3.3\Omega$		9.6	17.3		
T _{d(off)}	Turn-Off Delay Time	I _D =-3A		8.4	16.8 ns		
T _f	Fall Time			52	104		
C _{iss}	Input Capacitance			686			
Coss	Output Capacitance	V_{DS} =-10V , V_{GS} =0V , f=1MHz		90.8	pF		
C _{rss}	Reverse Transfer Capacitance			80.4			

Diode Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
I _S	Continuous Source Current ^{1,4}				-3.1	А
I _{SM}	Pulsed Source Current ^{2,4}	$V_{G}=V_{D}=0V$, Force Current			-15.5	А
V _{SD}	Diode Forward Voltage ²	V _{GS} =0V , I _S =-1A , T _J =25℃			-1	V
t _{rr}	Reverse Recovery Time			8.4		nS
Q _{rr}	Reverse Recovery Charge	IF=-3A , dI/dt=100A/µs , TJ=25℃		3.3		nC

Note :

1. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper,t<10sec.

2.The data tested by pulsed , pulse width $\,\leq\,$ 300us , duty cycle $\,\leq\,$ 2%

3. The power dissipation is limited by 150 $^\circ\!\mathbb{C}$ junction temperature

4. The data is theoretically the same as I_D and I_{DM} , in real applications, should be limited by total power dissipation.



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Typical Characteristics

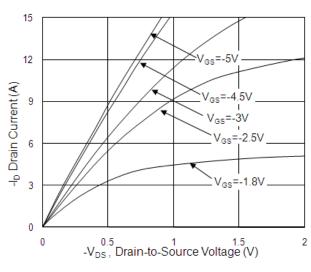


Fig.1 Typical Output Characteristics

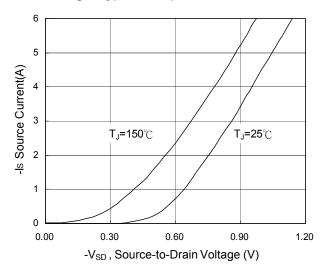


Fig.3 Forward Characteristics Of Reverse

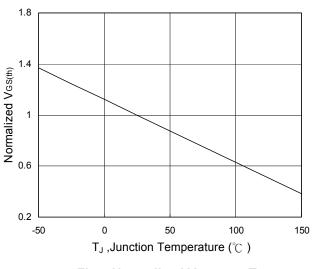


Fig.5 Normalized $V_{GS(th)}$ vs. T_J

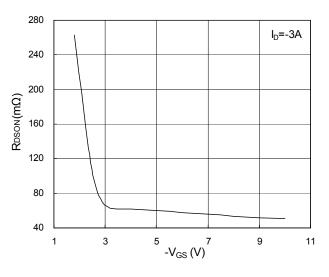


Fig.2 On-Resistance vs. Gate-Source

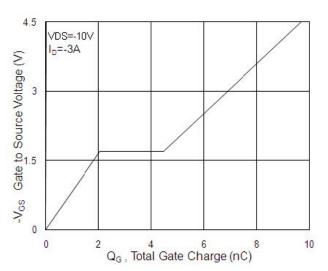


Fig.4 Gate-Charge Characteristics

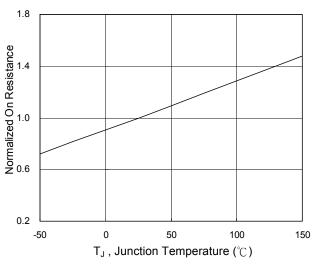


Fig.6 Normalized R_{DSON} vs. T_J



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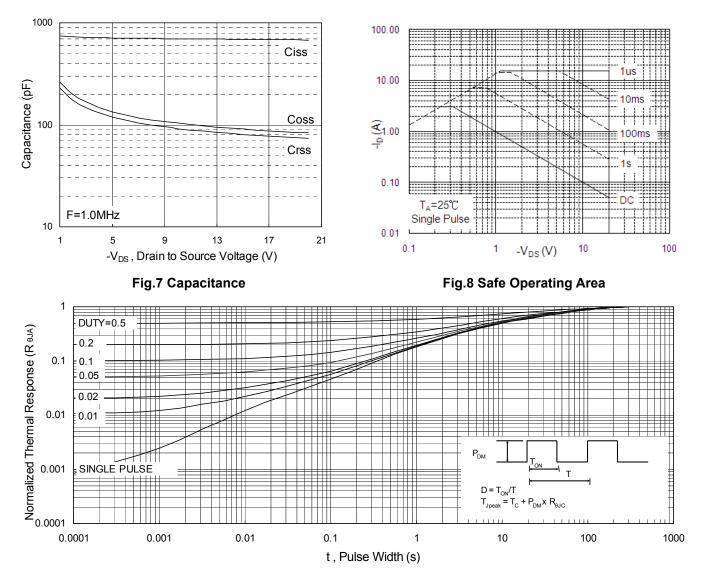


Fig.9 Normalized Maximum Transient Thermal Impedance

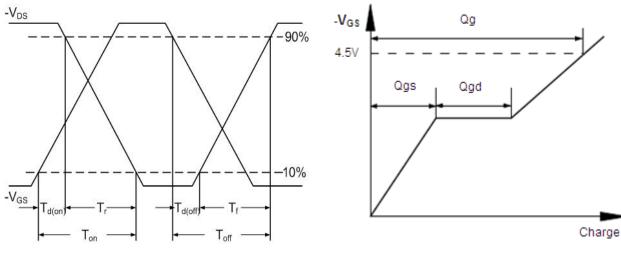


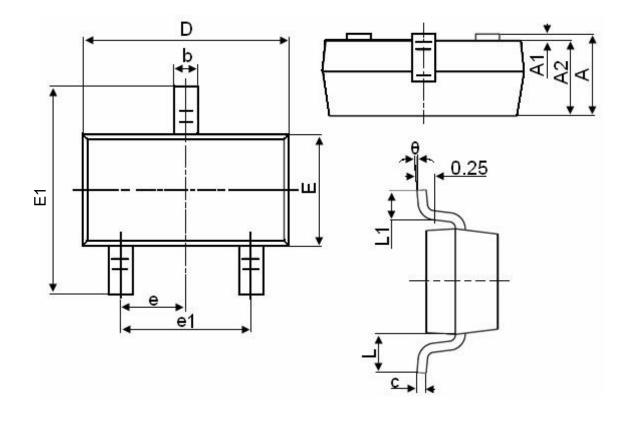
Fig.10 Switching Time Waveform

Fig.11 Gate Charge Waveform



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Packaging information



Currence of	Dimensions	in Millimeters		
Symbol	MIN.	MAX.		
А	0.900	1.150		
A1	0.000	0.100		
A2	0.900	1.050		
b	0.300	0.500		
С	0.080	0.150		
D	2.800	3.000		
E	1.200	1.400		
E1	2.250	2.550		
е	0.95	0.950TYP		
e1	1.800	2.000		
L	0.55	0.550REF		
L1	0.300	0.500		
θ	0°	8°		



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